

The QFN Lid Series was designed for Barry's C-QFN Air Cavity Family. There are several methods of attachment. Below are some of the more common methods.

QFN Lid Attachment Options:

Epoxy:

Ceramic lid is attached to the top surface of the package wall using B-stage non-conductive epoxy. We recommend our unmetallized lid configuration for this method (LID-XX-000).

This method does not result in a hermetic seal.

The leak rate of a properly sealed QFN package will be $<1 \times 10^{-8}$ atm cc/s He. We provide QFN packages and lids separately in an open configuration. Therefore we test in accordance with MIL-STD-883 method 1014 Test Condition A4 as appropriate for unlidded packages.

† The temperature required to melt even this type of glass may present problems depending on the characteristics of the semiconductor used and the attachment method.

Sealing Glass†:

Ceramic lid is attached to the top surface of the package wall using a low temperature glass.

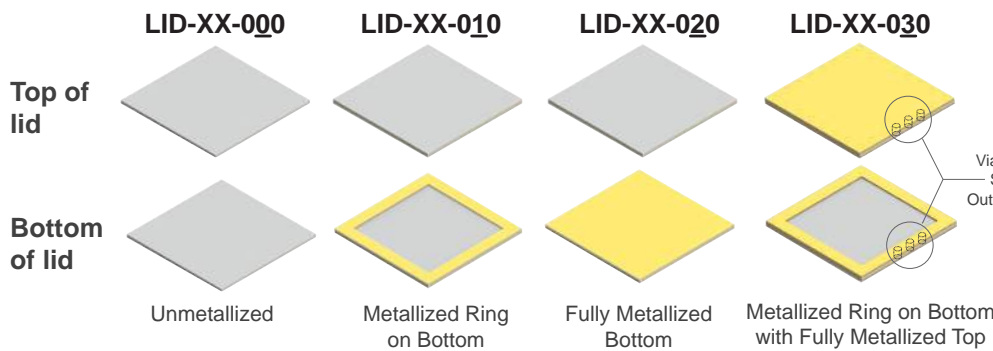
This method results in a hermetic seal.

Solder:

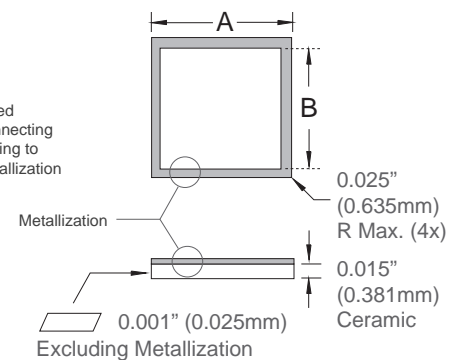
Metallized ceramic lid or metal lid is attached to the metallized top surface of the package wall. The most common alloy used is AuSn eutectic.

This method results in a hermetic seal.

QFN Lid Configurations:



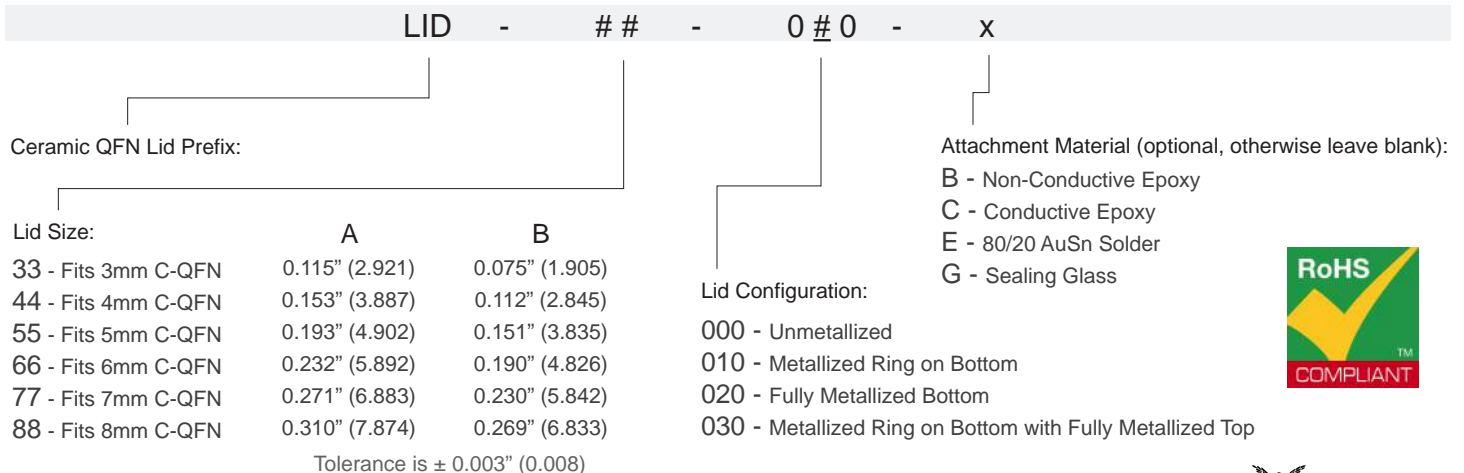
QFN Lid Dimensions:



Metallization: RoHS 50µ inches gold (min.) over 50µ inches nickel (min.) over tungsten or MoMN refractory metallization.

QFN Lid Ordering Information:

Example Part Number: LID-44-030



Barry Industries reserves the right to change part number and/or process without notification.

Barry Industries maintains an ISO9001 Certified Quality Management System.

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